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Ref: CiE/2026-27/KBR/GlobalTender/PSD-Binder-01 – Corrigendum01

Tender dated: 07-Aug-2026

Corrigendum 01 for Global Tender Notification for the Procurement of a Particle Size and Shape Analyser based on Dynamic Image Analysis for Measurements on Powders and similar materials

This is a corrigendum issued in reference to tender Ref: CiE/2026-27/KBR/GlobalTender/PSD-Binder-01 for the supply and installation of a “Particle Size and Shape Analyser based on Dynamic Image Analysis” at the Civil Engineering department, IISc Bangalore.

Corrigendum:

- (i) Section 3.1, Point 3 a.: may be read with a new added subpoint “vi. The bidder shall submit a compliance matrix for the below requirements clearly stating how the technical specification requirement is being met or exceeding by the proposed equipment. The bidder shall supply relevant data sheets / test reports / catalogues as supporting documents for the same and the same shall be cross referred in the compliance matrix. Merely qualitatively stating that the specification requirement is “complied” or “noted” or “as per your specification” or “Yes” or “Will be given at the time of supply” or “Will be complied” etc., is not acceptable. The bidder is liable to be rejected if incomplete information is provided.

The bidder shall submit the technical compliance in the following format example:

Sl No	Spec. Requirement	Proposed equipment specifications	Compliance (Yes/No)	Explanation / Details	Additional Remarks
6	The instrument shall be capable of measuring the particle size through laser diffraction for samples:	The proposed instrument is a xxxxxxxx	Yes/No	Refer to catalogue Pg X	
6a	The range of measurement of powders shall range from a	The proposed instrument can measure particle sizes of powders	Yes/No	Refer to catalogue Pg Y	

	minimum of 0.02 µm or lower to a maximum of 2000 µm or higher for wet dispersion, with no hardware adjustment.	from xx µm to yy µm.			
6c	The instrument shall utilize dual laser technology, consisting of red laser of wavelength between 780 nm to 830 nm, and a blue laser of wavelength between 405 nm to 450 nm.	The instrument utilizes a xx laser technology. The wavelength of the red laser is xx nm. The wavelength of the blue laser is yy nm.	Yes/No	Refer to catalogue Pg X Refer to catalogue Pg Y Refer to catalogue Pg Z	

”

- (ii) Section 4.1, Point 1 b. may be read as: “No optional accessories should be required to perform the above measurements, and the successful bidder must demonstrate the measurement of particle size and shape measurements using the provided instrument and accessory setup: (a) The instrument setup should be capable of measuring particle size using laser diffraction in both dry dispersion and wet dispersion (but not simultaneously), and, (b) The instrument setup shall be capable of measuring particle shape using dynamic image analysis (DIA) in wet dispersion.”
- (iii) Section 4.2, Point 6 a. may be read as “The range of measurement of particle sizes of powders shall range from a minimum of 0.01 µm or lower to a maximum of 2000 µm or higher for wet dispersion, with no hardware adjustment.”
- (iv) Section 4.2, Point 9 may be read as “The instrument and software shall provide the particle size, shape, volume, transparency, and number of particles.”
- (v) Section 4.2, Point 10 may be read as: “The instrument shall utilize a Single Camera or Multi Camera Technology, with resolutions of 1.2 megapixel or higher resolution which can photograph at a frame rate of 30 frames per second (fps) or higher.”

- (vi) Section 3.6 may be read as “The instrument is to be under warranty period of a minimum of two (2) years including free supply of spare parts, data analysis software, and faulty consumables from the date of functional installation. If any portion of the system is found to be defective, the defective system has to be replaced or rectified at the cost of the successful bidder within 45 days from the date of receipt of written communications from IISc, Bangalore. If there is any delay in replacement or rectification, the warranty period should be correspondingly extended.

Note that the instrument, when under warranty, should be repaired to meet its original functionality, or replaced within 45 days at the cost of the successful bidder. If the successful bidder is unable to repair / replace the equipment within 45 days from the date of receipt of written communications from IISc, Bangalore, it will be counted as a breach of contract and the bidder is liable to be barred from taking up future works at/with IISc, Bangalore.”